Overview: Stand-Alone Atomic Force Microscope (SA AFM)

Use the SA AFM for scanning almost any size and sape of sample. The stage can sit on top of an inverted microscope, a large structure, or on the optional xy sample stage. This tip scanning unit has an linearized XY scan range of 40 microns, and two different Z ceramics: a 7 micron high resolution Z scanner, and a large motion 17 micron Z scanner.

Advanced Features of the SA AFM Include:

- Flexible, stand alone design
- Scans any sample size
- Adaptable to inverted microscopes
- Linearized xy piezoelectric scanner
- Accommodates widest range of standard AFM probes
- All standard modes, including vibrating, non-vibrating, and phase
- Direct drive motorized probe approach
- Intuitive LabVIEW-based software for image capture

Using the industry standard light lever force sensor, all standard scanning modes are included with the system. Vibrating mode is used for high resolution and soft samples, while non-vibrating mode can be used for routine scanning. Also included with the system are phase and lateral force modes.

Control software, written in LabVIEW, is simple and intuitive to use. Differing windows walk users through the process: a pre-scan window helps align the AFM probe, a scanning window aids in acquiring images, a force position window measures force distance curves, and finally, a system window assists in altering system parameters.

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